











**TPS22975** 

SLVSDD0A-MAY 2016-REVISED JUNE 2016

# TPS22975 5.7-V, 6-A, 16-mΩ On-Resistance Load Switch

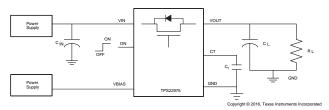
#### **Features**

- Integrated Single-Channel Load Switch
- Input Voltage Range: 0.6 V to V<sub>BIAS</sub>
- V<sub>BIAS</sub> Voltage Range: 2.5 V to 5.7 V
- On-Resistance (R<sub>ON</sub>)
  - R<sub>ON</sub> = 16 m $\Omega$  (typical) at VIN = 0.6 V to 5.7 V,  $V_{BIAS} = 5.7 V$
- 6-A Maximum Continuous Switch Current
- Low Quiescent Current
  - 37  $\mu$ A (typical) at  $V_{IN} = V_{BIAS} = 5 \text{ V}$
- Low-Control Input-Threshold Enables Use of 1.2-, 1.8-, 2.5-, and 3.3-V Logic
- Configurable Rise Time
- Thermal Shutdown
- Quick-Output Discharge (QOD) (Optional)
- SON 8-pin Package with Thermal Pad
- ESD Performance Tested per JESD 22
  - 2000-V HBM and 1000-V CDM

## Applications

- Ultrabook™
- Notebooks and Netbooks
- Tablet PC
- Consumer Electronics
- Set-top Boxes and Residential Gateways
- **Telecom Systems**
- Solid State Drives (SSDs)

## Simplified Schematic



## 3 Description

The TPS22975 product family consists of two devices: TPS22975 and TPS22975N. Each device is single-channel load switch that provides a configurable rise time to minimize inrush current. The device contains an N-channel MOSFET that can operate over an input voltage range of 0.6 V to 5.7 V and can support a maximum continuous current of 6 A. The switch is controlled by an on and off input (ON), which is capable of interfacing directly with lowvoltage control signals. TPS22975 has an optional 230-Ω on-chip load resistor for quick output discharge when switch is turned off.

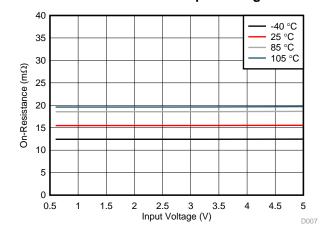
The TPS22975 is available in a small, space-saving 2-mm × 2-mm 8-pin SON package (DSG) with integrated thermal pad allowing for high power dissipation. The device is characterized for operation over the free-air temperature range of -40°C to +105°C.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TPS22975 TPS22975N	WSON (8)	2.00 mm × 2.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

#### On-Resistance vs Input Voltage



 $V_{BIAS} = 5 \text{ V}, I_{VOUT} = -200 \text{ mA}$ 



# **Table of Contents**

1	Features 1		9.3 Feature Description	15
2	Applications 1		9.4 Device Functional Modes	15
3	Description 1	10	Application and Implementation	16
4	Revision History2		10.1 Application Information	16
5	Device Comparison Table		10.2 Typical Application	16
6	Pin Configuration and Functions	11	Power Supply Recommendations	18
7	Specifications	12	Layout	19
•	7.1 Absolute Maximum Ratings		12.1 Layout Guidelines	19
	7.2 ESD Ratings		12.2 Layout Example	19
	7.3 Recommended Operating Conditions		12.3 Thermal Considerations	19
	7.4 Thermal Information	13	Device and Documentation Support	20
	7.5 Electrical Characteristics—V <sub>BIAS</sub> = 5 V		13.1 Device Support	20
	7.6 Electrical Characteristics—V <sub>BIAS</sub> = 2.5 V		13.2 Related Documentation	20
	7.7 Switching Characteristics		13.3 Receiving Notification of Documentation Update	es 20
	7.8 Typical DC Characteristics		13.4 Community Resources	20
	7.9 Typical AC Characteristics		13.5 Trademarks	20
8	Parameter Measurement Information		13.6 Electrostatic Discharge Caution	20
9	Detailed Description		13.7 Glossary	20
J	9.1 Overview	14	Mechanical, Packaging, and Orderable Information	20

# 4 Revision History

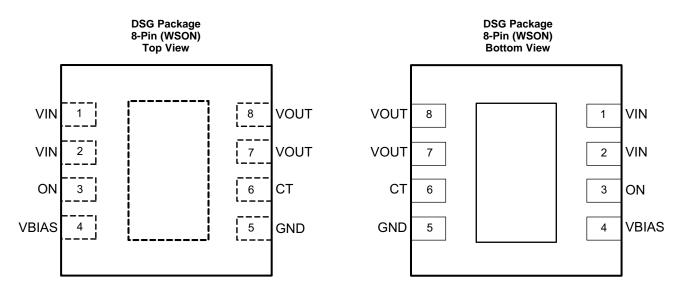
CI	hanges from Original (May 2016) to Revision A	Pag
•	Changed device status from Product Preview to Production Data .	



## 5 Device Comparison Table

DEVICE	R <sub>ON</sub> AT V <sub>IN</sub> = V <sub>BIAS</sub> = 5 V (TYPICAL)	QUICK-OUTPUT DISCHARGE	MAXIMUM OUTPUT CURRENT	ENABLE
TPS22975	16 mΩ	Yes	6 A	Active high
TPS22975N	16 mΩ	No	6 A	Active high

## 6 Pin Configuration and Functions



#### **Pin Functions**

	PIN	1/0	DESCRIPTION
NO.	NAME	1/0	DESCRIPTION
1	VIN		Switch input. Input bypass capacitor recommended for minimizing V <sub>IN</sub> dip. Must be connected to
2	VIIN	ı	Pin 1 and Pin 2. See the <i>Application and Implementation</i> section for more information
3	3 ON I		Active high switch control input. Do not leave floating
4 VBIAS I		I	Bias voltage. Power supply to the device. Recommended voltage range for this pin is 2.5 V to 5.7 V. See the <i>Application and Implementation</i> section for more information
5	GND	_	Device ground
6	СТ	0	Switch slew rate control. Can be left floating. See the <i>Adjustable Rise Time</i> section under <i>Feature Description</i> for more information
7	VOUT	0	Switch output
8	VOOT	U	Switch output
	Thermal Pad	_	Thermal pad (exposed center pad) to alleviate thermal stress. Tie to GND. See the <i>Layout Example</i> section for layout guidelines



## **Specifications**

#### 7.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted)(1)

ating need an temperature range (amose ethermos netea)			
	MIN	MAX	UNIT
Input voltage	-0.3	6	V
Output voltage	-0.3	6	V
Bias voltage	-0.3	6	V
On voltage	-0.3	6	V
Maximum continuous switch current		6	Α
Maximum pulsed switch current, pulse < 300 μs, 2% duty cycle		8	Α
Maximum junction temperature		125	°C
Storage temperature	-65	150	°C
	Input voltage Output voltage Bias voltage On voltage Maximum continuous switch current Maximum pulsed switch current, pulse < 300 µs, 2% duty cycle Maximum junction temperature	MIN Input voltage -0.3 Output voltage -0.3 Bias voltage -0.3 On voltage -0.3 Maximum continuous switch current Maximum pulsed switch current, pulse < 300 µs, 2% duty cycle Maximum junction temperature	Min         MAX           Input voltage         -0.3         6           Output voltage         -0.3         6           Bias voltage         -0.3         6           On voltage         -0.3         6           Maximum continuous switch current         6           Maximum pulsed switch current, pulse < 300 μs, 2% duty cycle

Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### 7.2 ESD Ratings

			VALUE	UNIT
V	Electrostatio discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000	V
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1000	

## 7.3 Recommended Operating Conditions

			MIN	MAX	UNIT
$V_{IN}$	Input voltage		0.6	$V_{BIAS}$	V
V <sub>BIAS</sub>	Bias voltage		2.5	5.7	V
V <sub>ON</sub>	ON voltage		0	5.7	V
V <sub>OUT</sub>	Output voltage			$V_{IN}$	V
	High lavel in put valtage. ON	V <sub>BIAS</sub> = 2.5 V to 5 V	1.1	5.7	V
V <sub>IH</sub>	High-level input voltage, ON	V <sub>BIAS</sub> = 5 V to 5.7 V	1.2	5.7	V
V <sub>IL</sub>	Low-level input voltage, ON	V <sub>BIAS</sub> = 2.5 V to 5.7 V	0	0.5	V
C <sub>IN</sub>	Input capacitor		1 <sup>(1)</sup>		μF
T <sub>A</sub>	Operating free-air temperature <sup>(</sup>	1)(2)	-40	105	°C

See the Application Information section.

JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process. JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

In applications where high power dissipation and-or poor package thermal resistance is present, the maximum ambient temperature may have to be derated and device lifetime may be affected. Maximum ambient temperature  $(T_{A(max)})$  is dependent on the maximum operating junction temperature  $(T_{J(max)})$ , the maximum power dissipation of the device in the application  $(P_{D(max)})$ , and the junction-to-ambient thermal resistance of the part-package in the application  $(\theta_{JA})$ , and can be approximated by the following equation:  $T_{A(max)} = T_{A(max)} = T$  $T_{J(max)} - (\theta_{JA} \times P_{D(max)}).$ 



#### 7.4 Thermal Information

		TPS22975	
	THERMAL METRIC <sup>(1)</sup>	DSG (WSON)	UNIT
		8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	74.8	°C/W
R <sub>0</sub> JC(top)	Junction-to-case (top) thermal resistance	81	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	44.7	°C/W
ΨЈТ	Junction-to-top characterization parameter	3.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	45.1	°C/W
R <sub>0</sub> JC(bot)	Junction-to-case (bottom) thermal resistance	16.4	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application

# 7.5 Electrical Characteristics— $V_{BIAS} = 5 \text{ V}$

Unless otherwise noted, the specifications in the following table applies where  $V_{BIAS} = 5 \text{ V}$ . Typical values are for  $T_A = 25 \text{ °C}$ .

	PARAMETER	TEST CON	DITIONS	T <sub>A</sub>	MIN TYP	MAX	UNIT
POWER SI	UPPLIES AND CURRENTS			1			
I <sub>Q, VBIAS</sub>	V <sub>BIAS</sub> quiescent current	$I_{OUT} = 0 A,$ $V_{IN} = V_{ON} = 5 V$		-40°C to +105°C	37	45	μΑ
I <sub>SD, VBIAS</sub>	V <sub>BIAS</sub> shutdown current	$V_{ON} = V_{OUT} = 0 V$		-40°C to +105°C		2.3	μΑ
			\/ F\/	-40°C to +85°C	0.005	5	
			$V_{IN} = 5 V$	-40°C to +105°C		10	
			V 22V	-40°C to +85°C	0.002	1.5	
	V off state cumbly current	V V 0V	V <sub>IN</sub> = 3.3 V	-40°C to +105°C		3.5	
I <sub>SD, VIN</sub>	V <sub>IN</sub> off-state supply current	$V_{ON} = V_{OUT} = 0 V$	V 40V	-40°C to +85°C	0.002	1	μΑ
			V <sub>IN</sub> = 1.8 V	-40°C to +105°C		2	
			.,	-40°C to +85°C	0.001	0.5	
			V <sub>IN</sub> = 0.6 V	-40°C to +105°C		1	
I <sub>ON</sub>	On-pin input leakage current	V <sub>ON</sub> = 5.5 V		-40°C to +105°C		0.1	μA
RESISTAN	ICE CHARACTERISTICS						
				25°C	16	19	mQ
			$V_{IN} = 5 V$	-40°C to +85°C		23	
				-40°C to +105°C		25	
			V <sub>IN</sub> = 3.3 V	25°C	16	19	
				-40°C to +85°C		23	
				-40°C to +105°C		25	
				25°C	16	19	
			$V_{IN} = 1.8 \text{ V}$	-40°C to +85°C		23	
В	On registeres	1 200 mA		-40°C to +105°C		25	
R <sub>ON</sub>	On-resistance	$I_{OUT} = -200 \text{ mA}$	V <sub>IN</sub> = 1.5 V	25°C	16	19	
				-40°C to +85°C		23	
				-40°C to +105°C		25	
				25°C	16	19	
			$V_{IN} = 1.05 \text{ V}$	-40°C to +85°C		23	
				-40°C to +105°C		25	
				25°C	16	19	
			$V_{IN} = 0.6 \ V$	-40°C to +85°C		23	1
				-40°C to +105°C		25	
V <sub>ON, HYS</sub>	On-pin hysteresis	V <sub>IN</sub> = 5 V	•	25°C	120		mV
R <sub>PD</sub> <sup>(1)</sup>	Output pulldown resistance	V <sub>IN</sub> = 5 V, V <sub>ON</sub> = 0 V		-40°C to +105°C	230	300	Ω
T <sub>SD</sub>	Thermal shutdown	Junction temperature ris	sing		160		°C
T <sub>SD, HYS</sub>	Thermal shutdown hysteresis	Junction temperature fa	alling		20		°C

Product Folder Links: TPS22975

(1) TPS22975 only



# 7.6 Electrical Characteristics— $V_{BIAS} = 2.5 \text{ V}$

Unless otherwise noted, the specifications in the following table applies where  $V_{BIAS} = 2.5 \text{ V}$ . Typical values are for  $T_A = 25 \text{ °C}$ .

	PARAMETER	TEST CON	IDITIONS	T <sub>A</sub>	MIN TYP	MAX	UNIT
POWER SI	UPPLIES AND CURRENTS						
I <sub>Q, VBIAS</sub>	V <sub>BIAS</sub> quiescent current	$I_{OUT} = 0 \text{ mA},$ $V_{IN} = V_{ON} = 2.5 \text{ V}$		-40°C to +105°C	14	20	μΑ
I <sub>SD, VBIAS</sub>	V <sub>BIAS</sub> shutdown current	V <sub>ON</sub> = V <sub>OUT</sub> = 0 V		-40°C to +105°C		1	μA
			V 0.5.V	-40°C to +85°C	0.005	1.3	
			$V_{IN} = 2.5 \text{ V}$	-40°C to +105°C		2.6	ı
			V 4.0.V	-40°C to +85°C	0.002	1	i
Ion	V	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	V <sub>IN</sub> = 1.8 V	-40°C to +105°C		2	
I <sub>SD, VIN</sub>	V <sub>IN</sub> off-state supply current	$V_{ON} = V_{OUT} = 0 V$	.,	-40°C to +85°C	0.002	0.8	μA
			V <sub>IN</sub> = 1.05 V	-40°C to +105°C		1.5	i
				-40°C to +85°C	0.001	0.5	i
			V <sub>IN</sub> = 0.6 V	-40°C to +105°C		1	ı
I <sub>ON</sub>	On-pin input leakage current	V <sub>ON</sub> = 5.5 V	1	-40°C to +105°C		0.1	μA
RESISTAN	ICE CHARACTERISTICS			1			
				25°C	20	26	mΩ
			V <sub>IN</sub> = 2.5 V	-40°C to +85°C		32	
				-40°C to +105°C		34	
			V <sub>IN</sub> = 1.8 V	25°C	18	23	
				-40°C to +85°C		29	
				-40°C to +105°C		31	
			V <sub>IN</sub> = 1.5 V	25°C	18	22	
R <sub>ON</sub>	On-resistance	I <sub>OUT</sub> = -200 mA		-40°C to +85°C		28	
				-40°C to +105°C		30	
				25°C	17	22	ı
			V <sub>IN</sub> = 1.2 V	-40°C to +85°C		27	
				-40°C to +105°C		29	
				25°C	17	21	
			V <sub>IN</sub> = 0.6 V	-40°C to +85°C		26	
				-40°C to +105°C		27	
V <sub>ON, HYS</sub>	On-pin hysteresis	V <sub>IN</sub> = 2.5 V	II.	25°C	85		mV
R <sub>PD</sub> <sup>(1)</sup>	Output pulldown resistance	V <sub>IN</sub> = 2.5 V, V <sub>ON</sub> = 0 V		-40°C to +105°C	230	330	Ω
T <sub>SD</sub>	Thermal shutdown	Junction temperature ri	sing		160		°C
T <sub>SD, HYS</sub>	Thermal shutdown hysteresis	Junction temperature fa			20		°C

<sup>(1)</sup> TPS22975 only

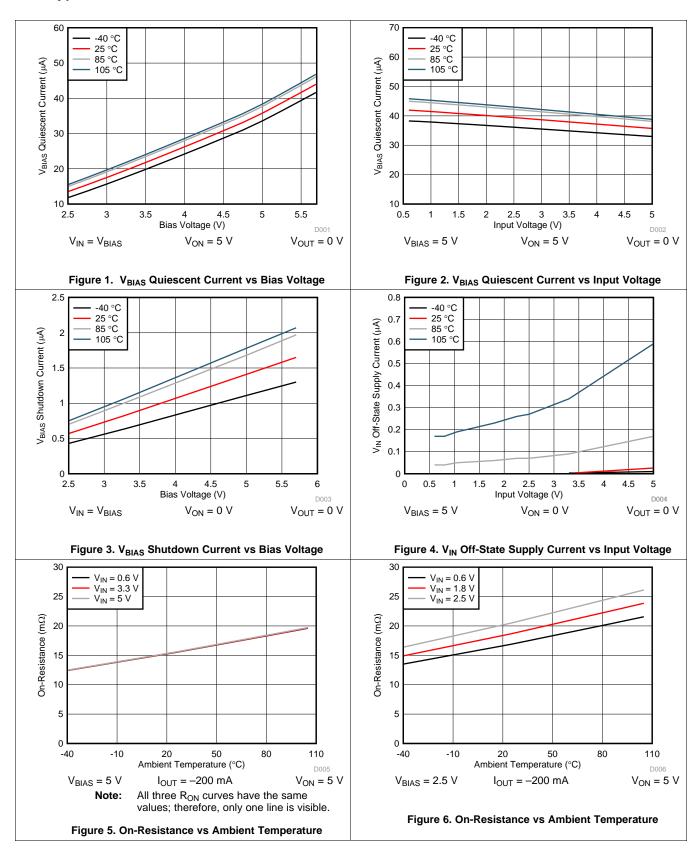


## 7.7 Switching Characteristics

DADAMETED		MINI TVD	BAAV	LINUT
		WIN ITP	WAX	UNIT
= V <sub>BIAS</sub> = 5 V, T <sub>A</sub> = 25°C (unle				
Turnon time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu F$ , $C_{IN} = 1 \mu F$ , $C_T = 1000 pF$ , $V_{ON} = 5 V$	1450		
Turnoff time	$R_L = 10~\Omega,~C_L = 0.1~\mu F,~C_{IN} = 1~\mu F,~C_T = 1000~p F,~V_{ON} = 5~V$	2		
V <sub>OUT</sub> rise time	$R_L = 10~\Omega,~C_L = 0.1~\mu F,~C_{IN} = 1~\mu F,~C_T = 1000~p F,~V_{ON} = 5~V$	1750		μs
V <sub>OUT</sub> fall time	$R_L = 10~\Omega,~C_L = 0.1~\mu F,~C_{IN} = 1~\mu F,~C_T = 1000~p F,~V_{ON} = 5~V$	2		
ON delay time	$R_L$ = 10 $\Omega$ , $C_L$ = 0.1 $\mu$ F, $C_{IN}$ = 1 $\mu$ F, $C_T$ = 1000 pF, $V_{ON}$ = 5 $V$	600		
= 0.6 V, V <sub>BIAS</sub> = 5 V, T <sub>A</sub> = 25°	C (unless otherwise noted)	•	·	
Turnon time	$R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V	620		
Turnoff time	$R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V	2		
V <sub>OUT</sub> rise time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	280		μs
V <sub>OUT</sub> fall time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	2		
ON delay time	$R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V	485		
= V <sub>BIAS</sub> = 2.5 V, T <sub>A</sub> = 25°C (ur	nless otherwise noted)			
Turnon time	$R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V	2180		
Turnoff time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	2		
V <sub>OUT</sub> rise time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	2150		μs
V <sub>OUT</sub> fall time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	2		
ON delay time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	1120		
= 0.6 V, V <sub>BIAS</sub> = 2.5 V, T <sub>A</sub> = 25	5°C (unless otherwise noted)			
Turnon time	$R_L = 10 \Omega$ , $C_L = 0.1 \mu$ F, $C_{IN} = 1 \mu$ F, $C_T = 1000 p$ F, $V_{ON} = 5 V$	1315		
Turnoff time	$R_L = 10 \ \Omega, \ C_L = 0.1 \ \mu F, \ C_{IN} = 1 \ \mu F, \ C_T = 1000 \ pF, \ V_{ON} = 5 \ V$	3		
V <sub>OUT</sub> rise time	$R_L = 10 \ \Omega, \ C_L = 0.1 \ \mu F, \ C_{IN} = 1 \ \mu F, \ C_T = 1000 \ pF, \ V_{ON} = 5 \ V$	650		μs
V <sub>OUT</sub> fall time	$R_L = 10 \ \Omega, \ C_L = 0.1 \ \mu F, \ C_{IN} = 1 \ \mu F, \ C_T = 1000 \ pF, \ V_{ON} = 5 \ V$	2		
ON delay time	$R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V	975		
	PARAMETER  E V <sub>BIAS</sub> = 5 V, T <sub>A</sub> = 25°C (unlet of the content of t	PARAMETER         TEST CONDITION           EV <sub>BIAS</sub> = 5 V, $T_A$ = 25°C (unless otherwise noted)           Turnon time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           Turnoff time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           VOUT fall time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           ON delay time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           • 0.6 V, $V_{BIAS}$ = 5 V, $T_A$ = 25°C (unless otherwise noted)           Turnoff time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           Vour fise time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           Vour fise time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           Vour fall time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           Vour fall time $R_L$ = 10 Ω, $C_L$ = 0.1 μF, $C_{IN}$ = 1 μF, $C_T$ = 1000 pF, $V_{ON}$ = 5 V           Value $R_L$ = 10 Ω, $R_L$ = 0.1 μF, $R_L$ = 1 μF, $R_L$ = 1000 pF, $R_L$ = 10 Ω, $R_L$ = 10 Ω, $R_L$ = 0.1 μF, $R_L$ = 1 μF, $R_L$ = 1000 pF, $R_L$ = 10 Ω, $R_L$ = 10 Ω, $R_L$ = 0.1 μF, $R_L$ = 1 μF, $R_L$ = 1000 pF, $R_L$ = 10 Ω, $R_L$ = 1 μF, $R_L$ = 1000 pF, $R_L$ = 1000 pF, $R_L$ = 1000 pF, $R$	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $



## 7.8 Typical DC Characteristics

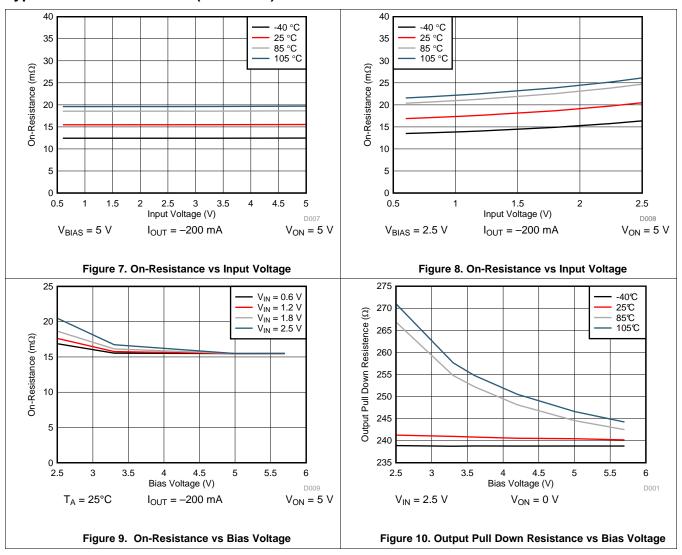


Submit Documentation Feedback

Copyright © 2016, Texas Instruments Incorporated



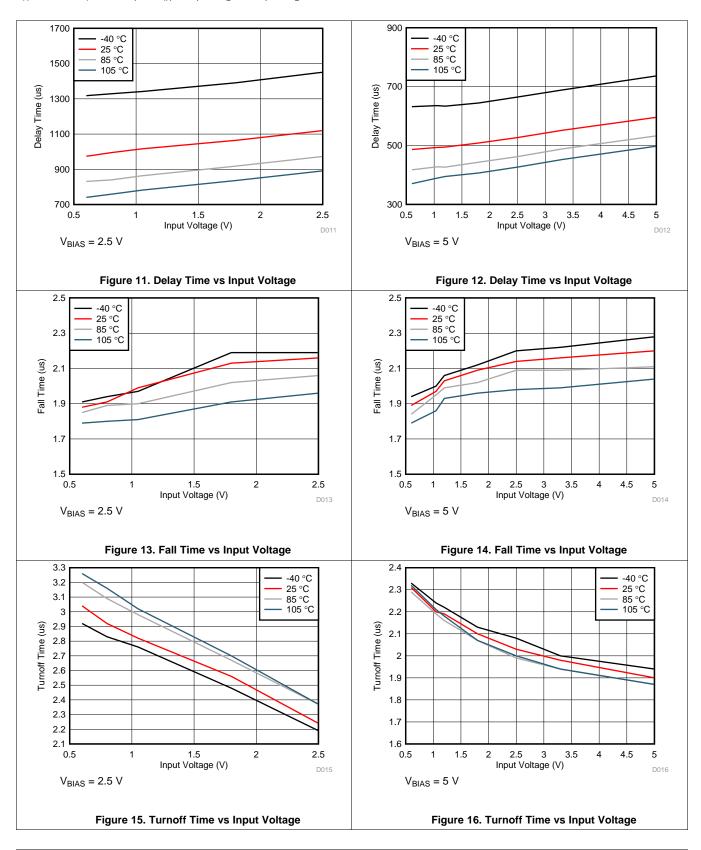
## **Typical DC Characteristics (continued)**





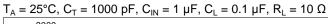
## 7.9 Typical AC Characteristics

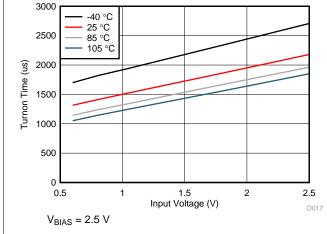
 $T_A = 25^{\circ}C$ ,  $C_T = 1000$  pF,  $C_{IN} = 1$   $\mu$ F,  $C_L = 0.1$   $\mu$ F,  $R_L = 10$   $\Omega$ 





## **Typical AC Characteristics (continued)**





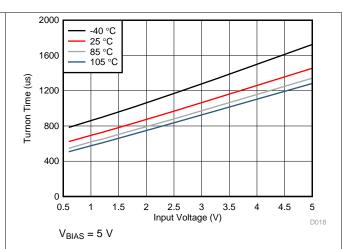
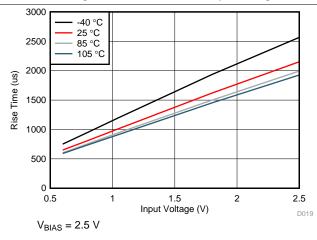


Figure 17. Turnon Time vs Input Voltage





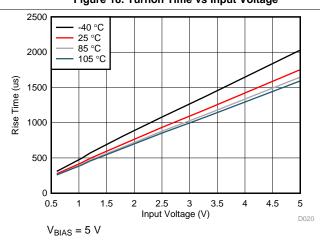
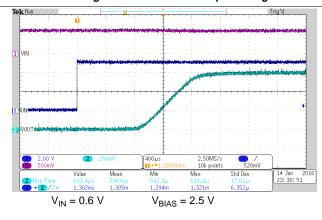


Figure 19. Rise Time vs Input Voltage

Figure 20. Rise Time vs Input Voltage



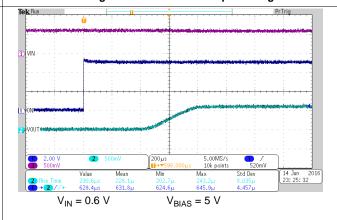
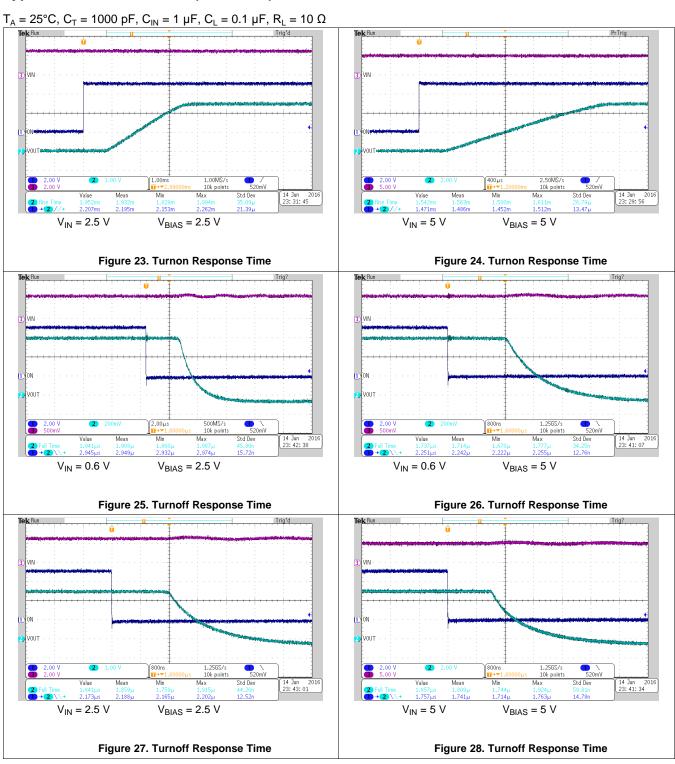


Figure 21. Turnon Response Time

Figure 22. Turnon Response Time

# TEXAS INSTRUMENTS

## **Typical AC Characteristics (continued)**

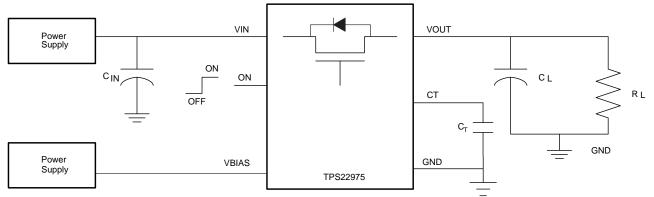


Submit Documentation Feedback

Copyright © 2016, Texas Instruments Incorporated



## 8 Parameter Measurement Information



Copyright © 2016, Texas Instruments Incorporated

- A. Rise and fall times of the control signal are 100 ns.
- B. Turnoff times and fall times are dependent on the time constant at the load. For the TPS22975, the internal pull-down resistance  $R_{PD}$  is enabled when the switch is disabled. The time constant is  $(R_{PD} \parallel R_L) \times C_L$ .

Figure 29. Test Circuit

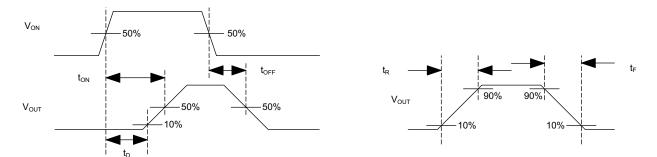


Figure 30.  $t_{ON}$  and  $t_{OFF}$  Waveforms



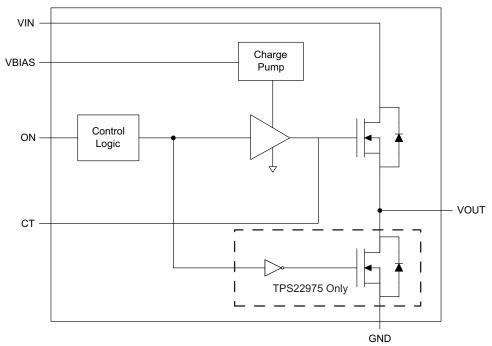
## 9 Detailed Description

#### 9.1 Overview

The TPS22975 device is a single-channel, 6-A load switch in an 8-pin SON package. To reduce the voltage drop in high current rails, the device implements an N-channel MOSFET. The device has a configurable slew rate for applications that require a specific rise-time.

The device prevents downstream circuits from pulling high standby current from the supply by limiting the leakage current of the device when it is disabled. The integrated control logic, driver, power supply, and output discharge FET eliminates the need for any external components, which reduces solution size and bill of materials (BOM) count.

## 9.2 Functional Block Diagram



Copyright © 2016, Texas Instruments Incorporated

(1)



#### 9.3 Feature Description

#### 9.3.1 Adjustable Rise Time

A capacitor to GND on the CT pin sets the slew rate. The voltage on the CT pin can be as high as 15 V; therefore, the minimum voltage rating for the CT capacitor must be 30 V for optimal performance. An approximate formula for the relationship between  $C_T$  and slew rate when  $V_{BIAS}$  is set to 5 V is shown in Equation 1. This equation accounts for 10% to 90% measurement on  $V_{OUT}$  and does not apply for  $C_T < 100$  pF. Use Table 1 to determine rise times for when  $C_T = 0$  pF.

$$SR = 0.43 \times CT + 26$$

#### where

- SR is the slew rate (in μs/V)
- C<sub>T</sub> is the capacitance value on the CT pin (in pF)
- The units for the constant 26 are μs/V. The units for the constant 0.43 are μs/(V x pF).

Rise time can be calculated by multiplying the input voltage by the slew rate. Table 1 contains rise time values measured on a typical device. Rise times shown in Table 1 are only valid for the power-up sequence where  $V_{IN}$  and  $V_{BIAS}$  are already in steady state condition before the ON pin is asserted high.

	Table 11 ties 1 ties 1 ties 2													
0 (		RISE TIME ( $\mu$ s) 10% - 90%, $C_L$ = 0.1 $\mu$ F, $C_{IN}$ = 1 $\mu$ F, $R_L$ = 10 $\Omega$ , $V_{BIAS}$ = 5 $V^{(1)}$												
C <sub>T</sub> (pF)	VIN = 5 V	VIN = 3.3 V	VIN = 1.8 V	VIN = 1.5 V	VIN = 1.2 V	VIN = 1.05 V	VIN = 0.6 V							
0	140	105	75	65	60	55	40							
220	520	360	215	185	160	140	95							
470	970	660	385	330	275	240	155							
1000	1750	1190	700	595	495	435	275							
2200	3875	2615	1520	1290	1070	940	595							
4700	7580	5110	2950	2510	2075	1830	1150							
10000	16980	11485	6650	5635	4685	4110	2595							

Table 1. Rise Time t<sub>R</sub> vs CT Capacitor

## 9.3.2 Quick-Output Discharge (QOD) (Optional)

The TPS22975 includes an optional QOD feature. When the switch is disabled, an internal discharge resistance is connected between VOUT and GND to remove the remaining charge from the output. This resistance has a typical value of 230  $\Omega$  and prevents the output from floating while the switch is disabled. For best results, it is recommended that the device gets disabled before  $V_{\text{BIAS}}$  falls below the minimum recommended voltage.

#### 9.3.3 Thermal Shutdown

Thermal shutdown protects the part from internally or externally generated excessive temperatures. When the device temperature triggers  $T_{SD}$  (typical 160°C), the switch is turned off. The switch automatically turns on again if the temperature of the die drops 20 degrees below the  $T_{SD}$  threshold.

#### 9.4 Device Functional Modes

The Table 2 lists the VOUT pin states as determined by the ON pin.

**Table 2. VOUT Connection** 

ON	TPS22975	TPS22975N
L	GND	Open
Н	VIN	VIN

<sup>(1)</sup> Typical Values at 25°C with a 25-V X7R 10% Ceramic Capacitor on CT



## 10 Application and Implementation

#### **NOTE**

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 10.1 Application Information

#### 10.1.1 ON and OFF Control

The ON pin controls the state of the switch. ON is active high and has a 1.2-V ON-pin enable threshold, making it capable of interfacing with low-voltage signals. The ON pin is compatible with standard GPIO logic thresholds. It can be used with any microcontroller with 1.2 V or higher GPIO voltage. This pin cannot be left floating and must be driven either high or low for proper functionality.

#### 10.1.2 Input Capacitor (C<sub>IN</sub>) (Optional)

To limit the voltage drop on the input supply caused by transient inrush currents when the switch turns on into a discharged load capacitor or short-circuit, a capacitor needs to be placed between VIN and GND. A 1- $\mu$ F ceramic capacitor,  $C_{IN}$ , placed close to the pins, is usually sufficient. Higher values of  $C_{IN}$  can be used to further reduce the voltage drop during high current applications. When switching heavy loads, it is recommended to have an input capacitor about 10 times higher than the output capacitor ( $C_{L}$ ) to avoid excessive voltage drop.

#### 10.1.3 Output Capacitor (C<sub>L</sub>) (Optional)

Because of the integrated body diode in the NMOS switch, a  $C_{IN}$  greater than  $C_{L}$  is highly recommended. A  $C_{L}$  greater than  $C_{IN}$  can cause  $V_{OUT}$  to exceed  $V_{IN}$  when the system supply is removed. This could result in current flow through the body diode from  $V_{OUT}$  to  $V_{IN}$ . A  $C_{IN}$  to  $C_{L}$  ratio of 10 to 1 is recommended for minimizing  $V_{IN}$  dip caused by inrush currents during startup; however, a 10 to 1 ratio for capacitance is not required for proper functionality of the device. A ratio smaller than 10 to 1 (such as 1 to 1) could cause slightly more  $V_{IN}$  dip upon turn-on because of inrush currents. This can be mitigated by increasing the capacitance on the CT pin for a longer rise time (see the *Adjustable Rise Time* section).

#### 10.2 Typical Application

For optimal  $R_{ON}$  performance, it is recommended to have  $V_{IN} \le V_{BIAS}$ . The device is functional if  $V_{IN} > V_{BIAS}$  but it exhibits  $R_{ON}$  greater than what is listed in the *Electrical Characteristics—V\_{BIAS} = 5 V* and *Electrical Characteristics—V\_{BIAS} = 2.5 V* tables.

Figure 31 demonstrates how the TPS22975 can be used to power downstream modules.

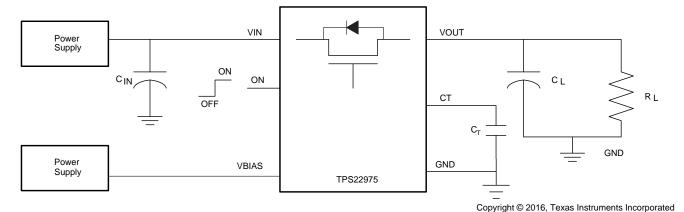


Figure 31. Powering a Downstream Module

Copyright © 2016, Texas Instruments Incorporated Product Folder Links: *TPS22975* 



#### **Typical Application (continued)**

#### 10.2.1 Design Requirements

DESIGN PARAMETER	EXAMPLE VALUE
V <sub>IN</sub>	3.3 V
V <sub>BIAS</sub>	5 V
C <sub>L</sub>	22 μF
Maximum Acceptable Inrush Current	400 mA

#### 10.2.2 Detailed Design Procedure

#### 10.2.2.1 Inrush Current

When the switch is enabled, the output capacitors must be charged up from 0 V to the set value (3.3 V in this example). This charge arrives in the form of inrush current. Inrush current can be calculated using Equation 2.

Inrush Current =  $C_L \times dV_{OUT}/dt$ 

#### Where:

- C<sub>1</sub> is the output capacitance
- dV<sub>OUT</sub> is the change in V<sub>OUT</sub> during the ramp up of the output voltage when device is enabled.
- dt is the rise time in V<sub>OUT</sub> during the ramp up of the output voltage when the device is enabled. (2)

The TPS22975 offers adjustable rise time for VOUT. This feature allows the user to control the inrush current during turnon. The appropriate rise time can be calculated using the design requirements and the inrush current equation as shown in Equation 3.

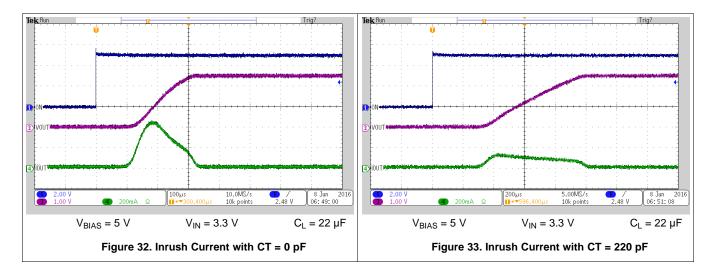
$$400 \text{ mA} = 22 \mu\text{F} \times 3.3 \text{ V/dt}$$
 (3)

The value of dt is given by Equation 4.

$$dt = 181.5 \,\mu s$$
 (4)

To ensure an inrush current of less than 400 mA, choose a CT value that yields a rise time of more than 181.5 µs. See the oscilloscope captures in the *Application Curves* section for an example of how the CT capacitor can be used to reduce inrush current.

#### 10.2.3 Application Curves





## 11 Power Supply Recommendations

The supply to the device must be well regulated and placed as close to the device terminal as possible with the recommended 1-µF bypass capacitor. If the supply is located more than a few inches from the device terminals, additional bulk capacitance may be required in addition to the ceramic bypass capacitors. If additional bulk capacitance is required, an electrolytic, tantalum or ceramic capacitor of 1 µF may be sufficient.

The TPS22975 operates regardless of power sequencing order. The order in which voltages are applied to  $V_{IN}$ ,  $V_{BIAS}$ , and ON does not damage the device as long as the voltages do not exceed the absolute maximum operating conditions. If voltage is applied to ON before  $V_{IN}$ , the slew rate of  $V_{OUT}$  can not be controlled.



## 12 Layout

## 12.1 Layout Guidelines

For best performance, all traces must be as short as possible. To be most effective, the input and output capacitors must be placed close to the device to minimize the effects that parasitic trace inductances may have on normal operation. Using wide traces for VIN, VOUT, and GND helps minimize the parasitic electrical effects along with minimizing the case to ambient thermal impedance. The CT trace must be as short as possible to reduce parasitic capacitance.

#### 12.2 Layout Example

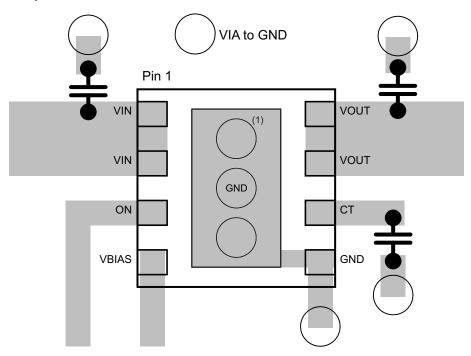


Figure 34. Layout Recommendation

#### 12.3 Thermal Considerations

The maximum IC junction temperature must be restricted to 125°C under normal operating conditions. To calculate the maximum allowable dissipation,  $P_{D(max)}$ , for a given ambient temperature, use Equation 5 as a guideline.

$$P_{D(max)} = \frac{T_{J(max)} - T_{A}}{\theta_{IA}}$$

where

- P<sub>D(max)</sub> is the maximum allowable power dissipation
- T<sub>J(max)</sub> is the maximum allowable junction temperature (125°C for the TPS22975)
- T<sub>A</sub> is the ambient temperature of the device
- Θ<sub>JA</sub> is the junction to air thermal impedance. See the *Thermal Information* section. This parameter is highly dependent upon board layout.

In Figure 34, notice that the thermal vias are located under the exposed thermal pad of the device. This allows for thermal diffusion away from the device.



## 13 Device and Documentation Support

## 13.1 Device Support

#### 13.1.1 Developmental Support

For the TPS22975 PSpice Transient Model, see SLVMBO6.

#### 13.2 Related Documentation

For related documentation see the following:

- Fundamentals of On-Resistance in Load Switches, SLVA771
- TPS22975 Load Switch Evaluation Module User's Guide, SLVUAR3

#### 13.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 13.4 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 13.5 Trademarks

E2E is a trademark of Texas Instruments.

Ultrabook is a trademark of Intel.

All other trademarks are the property of their respective owners.

#### 13.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 13.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.





1-Jul-2016

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TPS22975DSGR	ACTIVE	WSON	DSG	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	13XH	Samples
TPS22975DSGT	ACTIVE	WSON	DSG	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	13XH	Samples
TPS22975NDSGR	ACTIVE	WSON	DSG	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	14YH	Samples
TPS22975NDSGT	ACTIVE	WSON	DSG	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	14YH	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



## **PACKAGE OPTION ADDENDUM**

1-Jul-2016

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

www.ti.com 13-Feb-2017

## TAPE AND REEL INFORMATION





Α0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

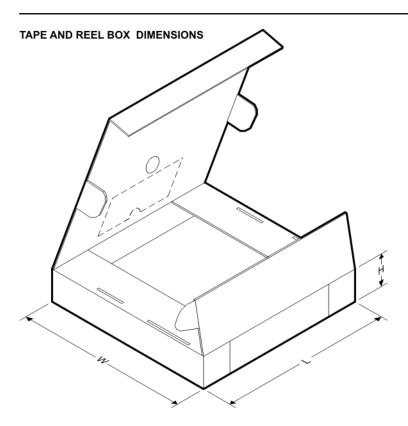
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS22975DSGR	WSON	DSG	8	3000	180.0	8.4	2.3	2.3	1.15	4.0	8.0	Q2
TPS22975DSGT	WSON	DSG	8	250	180.0	8.4	2.3	2.3	1.15	4.0	8.0	Q2
TPS22975NDSGR	WSON	DSG	8	3000	180.0	8.4	2.3	2.3	1.15	4.0	8.0	Q2
TPS22975NDSGR	WSON	DSG	8	3000	180.0	8.4	2.3	2.3	1.15	4.0	8.0	Q2
TPS22975NDSGT	WSON	DSG	8	250	180.0	8.4	2.3	2.3	1.15	4.0	8.0	Q2
TPS22975NDSGT	WSON	DSG	8	250	180.0	8.4	2.3	2.3	1.15	4.0	8.0	Q2

www.ti.com 13-Feb-2017

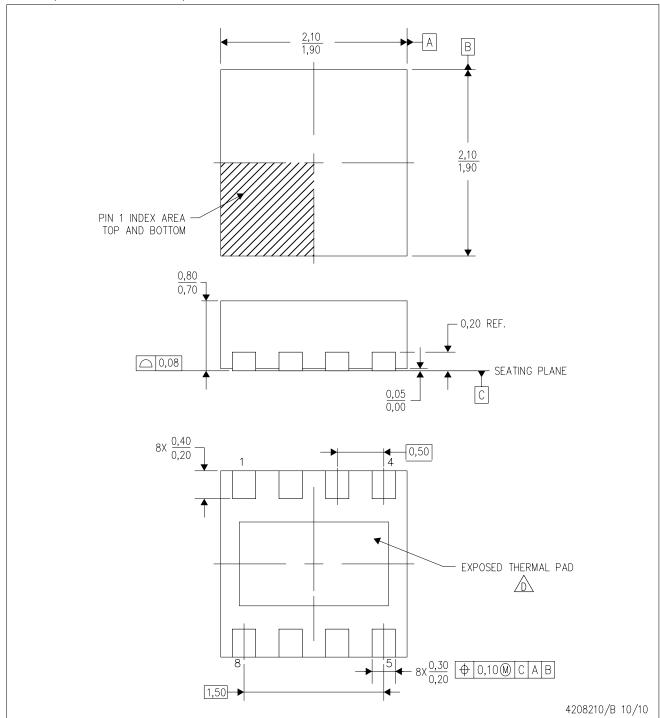


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS22975DSGR	WSON	DSG	8	3000	210.0	185.0	35.0
TPS22975DSGT	WSON	DSG	8	250	210.0	185.0	35.0
TPS22975NDSGR	WSON	DSG	8	3000	210.0	185.0	35.0
TPS22975NDSGR	WSON	DSG	8	3000	210.0	185.0	35.0
TPS22975NDSGT	WSON	DSG	8	250	210.0	185.0	35.0
TPS22975NDSGT	WSON	DSG	8	250	210.0	185.0	35.0

DSG (S-PWSON-N8)

PLASTIC SMALL OUTLINE NO-LEAD



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- This drawing is subject to change without notice.
- Quad Flatpack, No-Leads (QFN) package configuration.
- The package thermal pad must be soldered to the board for thermal and mechanical performance.

See the Product Data Sheet for details regarding the exposed thermal pad dimensions.

E. Falls within JEDEC MO-229.



# DSG (S-PWSON-N8)

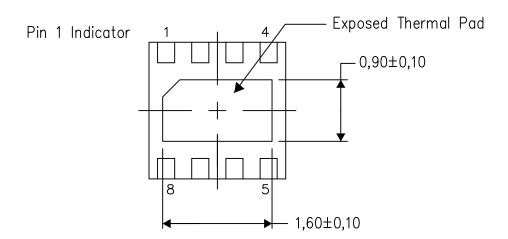
PLASTIC SMALL OUTLINE NO-LEAD

#### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

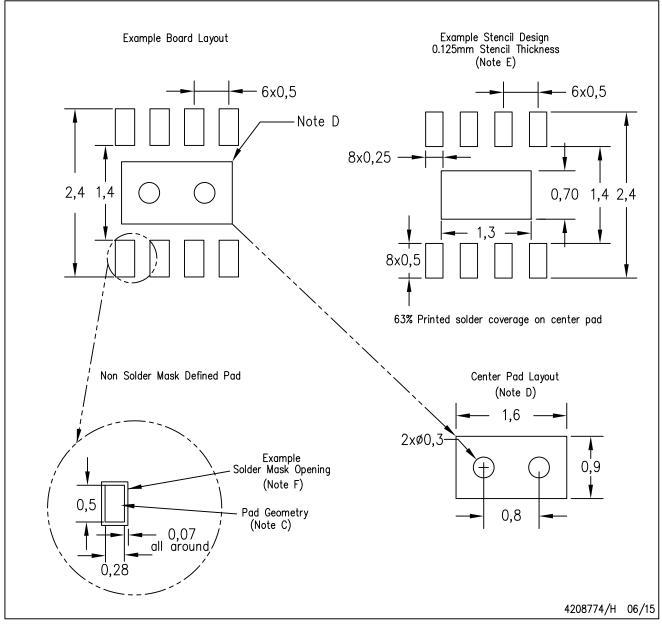
4208347/I 06/15

NOTE: All linear dimensions are in millimeters



# DSG (S-PWSON-N8)

## PLASTIC SMALL OUTLINE NO-LEAD



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <a href="https://www.ti.com">http://www.ti.com</a>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for solder mask tolerances.



#### **IMPORTANT NOTICE**

Texas Instruments Incorporated (TI) reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete.

TI's published terms of sale for semiconductor products (http://www.ti.com/sc/docs/stdterms.htm) apply to the sale of packaged integrated circuit products that TI has qualified and released to market. Additional terms may apply to the use or sale of other types of TI products and services.

Reproduction of significant portions of TI information in TI data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such reproduced documentation. Information of third parties may be subject to additional restrictions. Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyers and others who are developing systems that incorporate TI products (collectively, "Designers") understand and agree that Designers remain responsible for using their independent analysis, evaluation and judgment in designing their applications and that Designers have full and exclusive responsibility to assure the safety of Designers' applications and compliance of their applications (and of all TI products used in or for Designers' applications) with all applicable regulations, laws and other applicable requirements. Designer represents that, with respect to their applications, Designer has all the necessary expertise to create and implement safeguards that (1) anticipate dangerous consequences of failures, (2) monitor failures and their consequences, and (3) lessen the likelihood of failures that might cause harm and take appropriate actions. Designer agrees that prior to using or distributing any applications that include TI products, Designer will thoroughly test such applications and the functionality of such TI products as used in such applications.

TI's provision of technical, application or other design advice, quality characterization, reliability data or other services or information, including, but not limited to, reference designs and materials relating to evaluation modules, (collectively, "TI Resources") are intended to assist designers who are developing applications that incorporate TI products; by downloading, accessing or using TI Resources in any way, Designer (individually or, if Designer is acting on behalf of a company, Designer's company) agrees to use any particular TI Resource solely for this purpose and subject to the terms of this Notice.

TI's provision of TI Resources does not expand or otherwise alter TI's applicable published warranties or warranty disclaimers for TI products, and no additional obligations or liabilities arise from TI providing such TI Resources. TI reserves the right to make corrections, enhancements, improvements and other changes to its TI Resources. TI has not conducted any testing other than that specifically described in the published documentation for a particular TI Resource.

Designer is authorized to use, copy and modify any individual TI Resource only in connection with the development of applications that include the TI product(s) identified in such TI Resource. NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT OF TI OR ANY THIRD PARTY IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information regarding or referencing third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of TI Resources may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI RESOURCES ARE PROVIDED "AS IS" AND WITH ALL FAULTS. TI DISCLAIMS ALL OTHER WARRANTIES OR REPRESENTATIONS, EXPRESS OR IMPLIED, REGARDING RESOURCES OR USE THEREOF, INCLUDING BUT NOT LIMITED TO ACCURACY OR COMPLETENESS, TITLE, ANY EPIDEMIC FAILURE WARRANTY AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY DESIGNER AGAINST ANY CLAIM, INCLUDING BUT NOT LIMITED TO ANY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON ANY COMBINATION OF PRODUCTS EVEN IF DESCRIBED IN TI RESOURCES OR OTHERWISE. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, DIRECT, SPECIAL, COLLATERAL, INDIRECT, PUNITIVE, INCIDENTAL, CONSEQUENTIAL OR EXEMPLARY DAMAGES IN CONNECTION WITH OR ARISING OUT OF TI RESOURCES OR USE THEREOF, AND REGARDLESS OF WHETHER TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES.

Unless TI has explicitly designated an individual product as meeting the requirements of a particular industry standard (e.g., ISO/TS 16949 and ISO 26262), TI is not responsible for any failure to meet such industry standard requirements.

Where TI specifically promotes products as facilitating functional safety or as compliant with industry functional safety standards, such products are intended to help enable customers to design and create their own applications that meet applicable functional safety standards and requirements. Using products in an application does not by itself establish any safety features in the application. Designers must ensure compliance with safety-related requirements and standards applicable to their applications. Designer may not use any TI products in life-critical medical equipment unless authorized officers of the parties have executed a special contract specifically governing such use. Life-critical medical equipment is medical equipment where failure of such equipment would cause serious bodily injury or death (e.g., life support, pacemakers, defibrillators, heart pumps, neurostimulators, and implantables). Such equipment includes, without limitation, all medical devices identified by the U.S. Food and Drug Administration as Class III devices and equivalent classifications outside the U.S.

TI may expressly designate certain products as completing a particular qualification (e.g., Q100, Military Grade, or Enhanced Product). Designers agree that it has the necessary expertise to select the product with the appropriate qualification designation for their applications and that proper product selection is at Designers' own risk. Designers are solely responsible for compliance with all legal and regulatory requirements in connection with such selection.

Designer will fully indemnify TI and its representatives against any damages, costs, losses, and/or liabilities arising out of Designer's non-compliance with the terms and provisions of this Notice.